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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	180MHz
Connectivity	CANbus, CSIO, EBI/EMI, Ethernet, I ² C, LINbus, SD, SmartCard, SPI, UART/USART, USB
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	121
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	192K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 24x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/s6e2gm8hhagv2000a



S6E2G Series

32-bit ARM® Cortex®-M4F FM4 Microcontroller

S6E2G Series are FM4 devices with up to 180 MHz CPU, 1 MB flash, 192 KB SRAM, 20x communication peripherals, 33x digital peripherals and 3x analog peripherals. They are designed for industrial automation and metering applications.

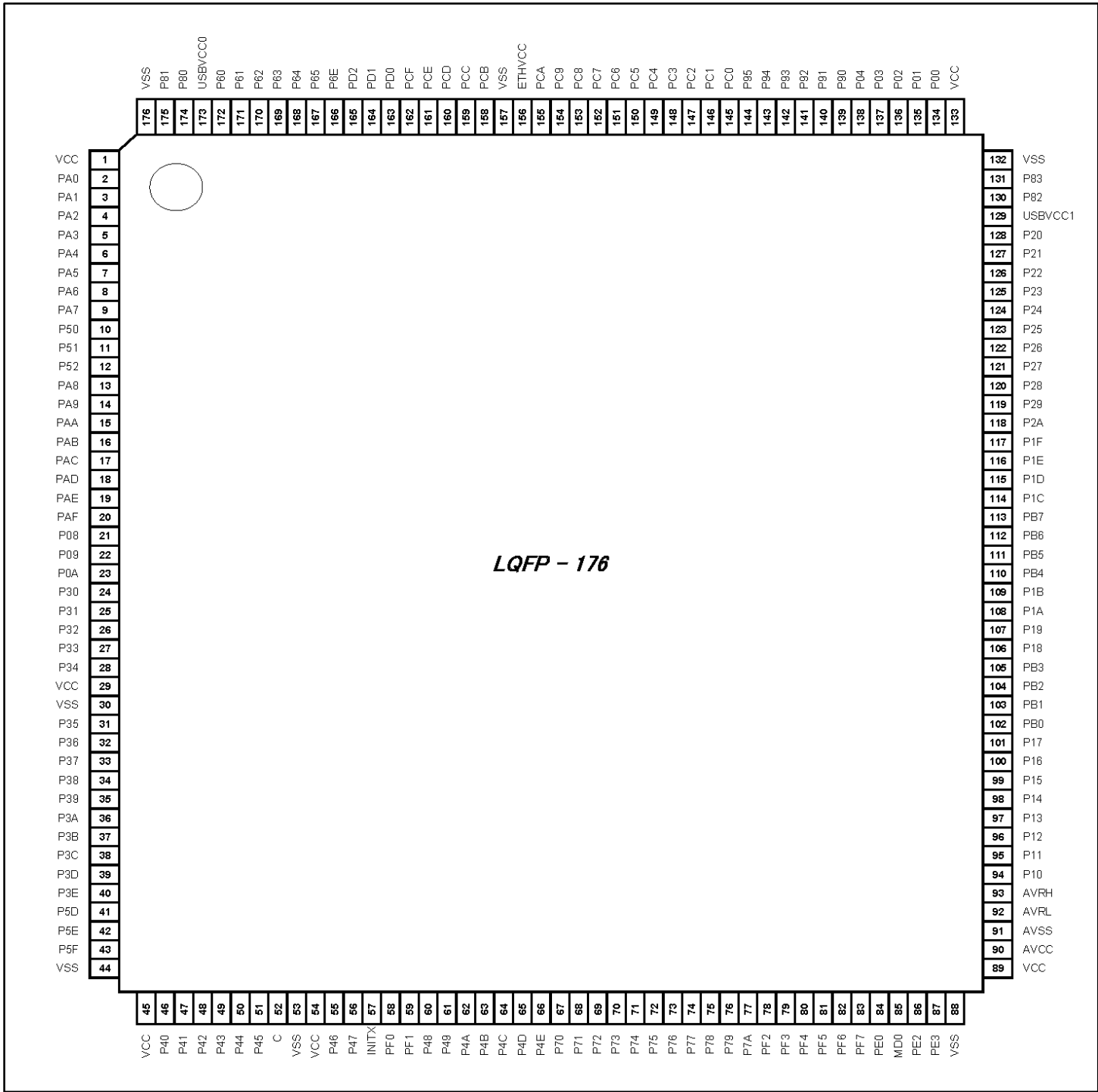
Devices in the S6E2G Series are highly integrated 32-bit microcontrollers with high performance and competitive cost. This series is based on the ARM Cortex-M4F processor with on-chip flash memory and SRAM. The series has peripherals such as motor control timers, A/D converters, and communications interfaces (USB, CAN, UART, CSIO (SPI), I²C, LIN). The products that are described in this data sheet are placed into TYPE5-M4 product categories in the "FM4 Family Peripheral Manual Main Part (002-04856)".

- 32-bit ARM Cortex-M4F Core
 - Up to 180 MHz frequency operation
- On-chip Memories
 - Flash memory: Up to 1024 Kbytes
 - SRAM memory:
 - SRAM0: up to 128 Kbytes
 - SRAM1: 32 Kbytes
 - SRAM2: 32 Kbytes
- Direct Memory Access (DMA) Controller (Eight Channels)
- Descriptor System Data Transfer Controller (DSTC); 256 channels
- External Bus Interface
- USB Interface (Max two channels): Host and Device
- CAN Interface (Max one channel) Available on S6E2GM and S6E2GH Devices Only
- Multi-function Serial Interface (Max 10 Channels)
 - UART (Universal Asynchronous Receiver/Transmitter)
 - Clock Synchronous Serial Interface (CSIO (SPI))
 - Local Interconnect Network (LIN)
 - Inter-Integrated Circuit (I²C)
 - Inter-IC Sound (I²S)
- Base Timer (Max 16 channels)
- General Purpose I/O Port
 - Up to 121 high-speed general-purpose I/O ports in 144-pin package
 - Up to 153 high-speed general-purpose I/O ports in 176-pin package
- Multi-function Timer (Max two units)
- Real-Time Clock (RTC)
- Analog to Digital Converter (ADC) (Max 32 Channels)
- Dual Timer (32-/16-bit Down Counter)
- Quadrature Position/Revolution Counter (QPRC; Max two channels)
- Watch Counter
- External Interrupt Controller Unit
- Watchdog Timer (Two channels)
- Cyclic Redundancy Check (CRC) Accelerator
- SD Card Interface Available on S6E2GM, S6E2GH, and S6E2GK Devices Only
- Ethernet-MAC Available on S6E2GM, S6E2GK, and S6E2G2 Devices only
- Smartcard Interface (Max 2 channels)
- Five Clock Sources
- Six Reset Sources
- Clock Supervisor (CSV)
- Low-Voltage Detector (LVD)
- Six Low-power Consumption Modes
 - Sleep
 - Timer
 - RTC
 - Stop
 - Deep standby RTC
 - Deep standby stop
- Peripheral Clock Gating System
- Crypto Assist Function
- Debug
 - Serial wire JTAG debug port (SWJ-DP)
 - Embedded trace macrocells (ETM) provide comprehensive debug and trace facilities.
 - AHB trace macrocells (HTM)
- 41-bit Unique ID
- Wide range voltage: VCC = 2.7 to 5.5 V



S6E2G Series

LQP176



Note:

- Only the GPIO function is shown on GPIO pins. See the table in [Pin Descriptions](#) for the full, multiplexed signal name.

Pin Number		Pin Name	I/O Circuit Type	Pin State Type
LQFP-176	LQFP-144			
119	95	P29	F	M
		AN25		
		SCK5_0 (SCL5_0)		
		INT09_2		
		MAD13_0		
120	96	P28	F	M
		AN26		
		SOT5_0 (SDA5_0)		
		INT10_2		
		MAD14_0		
121	97	P27	F	M
		AN27		
		SIN5_0		
		INT24_0		
		MAD15_0		
122	98	P26	E	M
		ADTG_6		
		TIOA6_2		
		INT11_2		
		MAD16_0		
123	99	P25	F	M
		AN28		
		TIOB6_2		
		INT25_0		
		MAD17_0		
124	100	P24	F	L
		AN29		
		TIOA13_1		
		MAD18_0		
125	101	P23	F	L
		UHCONX1		
		AN30		
		SCK0_0 (SCL0_0)		
		TIOB13_1		
126	102	P22	E	M
		AN31		
		SOT0_0 (SDA0_0)		
		INT26_0		

Pin Number		Pin Name	I/O Circuit Type	Pin State Type
LQFP-176	LQFP-144			
127	103	P21	I	K
		ADTG_4		
		SIN0_0		
		INT27_0		
		CROUT_0		
128	104	P20	I	F
		NMIX		
		WKUP0		
129	105	USBVCC1	-	-
130	106	P82	H	R
		UDM1		
131	107	P83	H	R
		UDP1		
132	108	VSS	-	-
133	109	VCC	-	-
134	110	P00	E	G
		TRSTX		
135	111	P01	E	G
		TCK		
		SWCLK		
136	112	P02	E	G
		TDI		
137	113	P03	E	G
		TMS		
		SWDIO		
138	114	P04	E	G
		TDO		
		SWO		
139	-	P90	E	K
		RTO10_1 (PPG10_1)		
		TIOB0_1		
		INT12_1		
		IC0_CLK_1		
140	-	P91	E	K
		SIN5_1		
		RTO11_1 (PPG11_1)		
		TIOB1_1		
		INT13_1		
		IC0_VCC_1		

Pin Number		Pin Name	I/O Circuit Type	Pin State Type
LQFP-176	LQFP-144			
166	136	P6E	E	W
		ADTG_5		
		SCK4_1 (SCL4_1)		
		INT29_0		
		E_PPS		
167	-	P65	E	K
		INT28_1		
168	-	P64	I	K
		CTS4_0		
		INT29_1		
169	137	P63	L	K
		ADTG_3		
		RTS4_0		
		INT30_0		
		MOEX_0		
170	138	P62	L	I
		SCK4_0 (SCL4_0)		
		TIOB7_2		
		MWEX_0		
171	139	P61	L	I
		UHCONX0		
		SOT4_0 (SDA4_0)		
		TIOA7_2		
		MALE_0		
		RTCCO_0		
		SUBOUT_0		
172	140	P60	I	Q
		SIN4_0		
		INT31_0		
		WKUP3		
173	141	USBVCC0	-	-
174	142	P80	H	R
		UDM0		
175	143	P81	H	R
		UDP0		
176	144	VSS	-	-

Module	Pin Name	Function	Pin Number	
			LQFP 176	LQFP 144
GPIO	P70	General-purpose I/O port 7	67	57
	P71		68	58
	P72		69	59
	P73		70	60
	P74		71	61
	P75		72	62
	P76		73	63
	P77		74	64
	P78		75	65
	P79		76	66
	P7A		77	67
	P80	General-purpose I/O port 8	174	142
	P81		175	143
	P82		130	106
	P83		131	107
	P90	General-purpose I/O port 9	139	-
	P91		140	-
	P92		141	-
	P93		142	-
	P94		143	-
	P95		144	-
	PA0	General-purpose I/O port A	2	2
	PA1		3	3
	PA2		4	4
	PA3		5	5
	PA4		6	6
	PA5		7	7
	PA6		8	8
	PA7		9	9
	PA8		13	10
	PA9		14	11
	PAA		15	12
	PAB		16	13
	PAC		17	14
	PAD		18	15
	PAE		19	16
	PAF		20	17

Latch-Up

Semiconductor devices are constructed by the formation of p-type and n-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic pnpn junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred milliamps to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
2. Be sure that abnormal current flows do not occur during the power-on sequence.

Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

Fail-Safe Design

As previously mentioned, all semiconductor devices have inherent rates of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

Precautions Related to Usage of Devices

Cypress semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

8.2 Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under Cypress' recommended conditions. For detailed information about mount conditions, contact your sales representative.

Lead Insertion Type

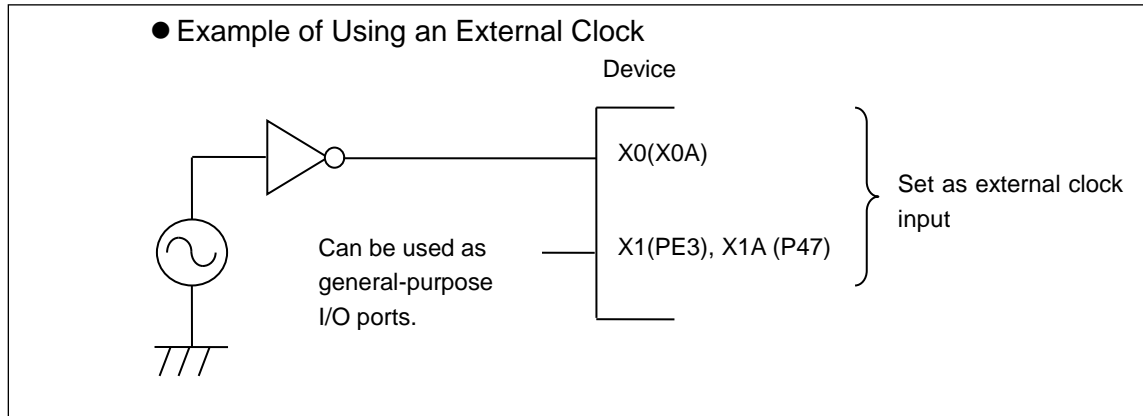
Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to Cypress recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

Using an External Clock

When using an external clock as an input of the main clock, set X0/X1 to the external clock input, and input the clock to X0. X1(PE3) can be used as a general-purpose I/O port. Similarly, when using an external clock as an input of the sub clock, set X0A/X1A to the external clock input and input the clock to X0A. X1A (P47) can be used as a general-purpose I/O port.

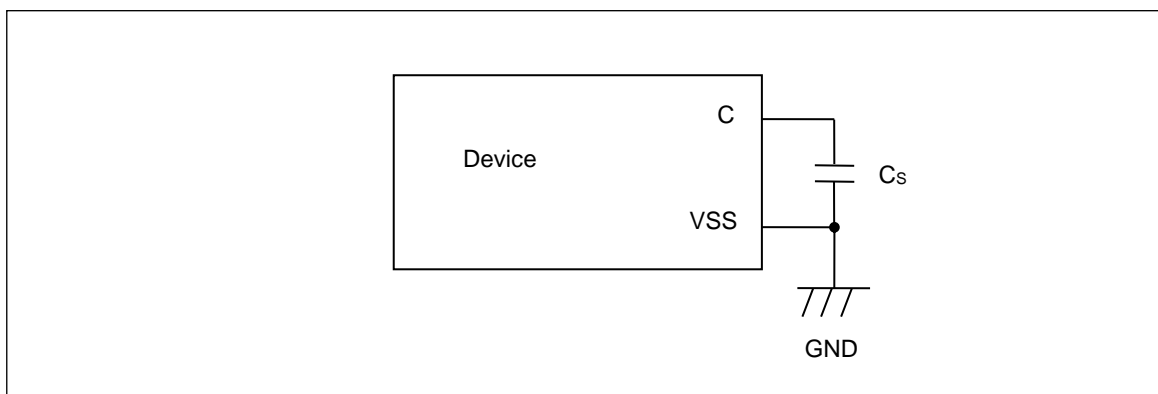


Handling When Using Multi-Function Serial Pin as I²C Pin

If the application uses the multi-function serial pin as an I²C pin, the P-channel transistor of the digital output must be disabled. I²C pins need to conform to electrical limitations like other pins, however, and avoid connecting to live external systems with the MCU power off.

C Pin

Devices in this series contain a regulator. Be sure to connect a smoothing capacitor (C_s) for the regulator between the C pin and the GND pin. Please use a ceramic capacitor or a capacitor of equivalent frequency characteristics as a smoothing capacitor. Some laminated ceramic capacitors have a large capacitance variation due to thermal fluctuation. Please select a capacitor that meets the specifications in the operating conditions to use by evaluating the temperature characteristics of the device. A smoothing capacitor of about 4.7 μF would be recommended for this series.



Mode Pins (MD0)

Connect the MD pin (MD0) directly to VCC or VSS pins. Design the printed circuit board such that the pull-up/down resistance stays low, the distance between the mode pins and VCC pins or VSS pins is as short as possible, and the connection impedance is low when the pins are pulled up/down such as for switching the pin level and rewriting the flash memory data. This is important to prevent the device from erroneously switching to test mode as a result of noise.

Table 12-3 Typical and Maximum Current Consumption in Normal Operation (PLL), Code with Data Accessing Running from Flash Memory (Flash 0 Wait-Cycle Mode and Read Access 0 Wait)

Parameter	Symbol	Pin Name	Conditions		Frequency ^{*4}	Value		Unit	Remarks
						Typ ^{*1}	Max ^{*2}		
Power supply current	I _{CC}	VCC	Normal operation ^{*6,*7} (PLL)	*5	72 MHz	54	112	mA	*3 When all peripheral clocks are on
					60 MHz	47	105	mA	
					48 MHz	39	97	mA	
					36 MHz	31	89	mA	
					24 MHz	23	81	mA	
					12 MHz	14	72	mA	
					8 MHz	11	69	mA	
					4 MHz	7.2	65	mA	
				*5	72 MHz	37	95	mA	*3 When all peripheral clocks are off
					60 MHz	33	91	mA	
					48 MHz	28	86	mA	
					36 MHz	23	81	mA	
					24 MHz	17	75	mA	
					12 MHz	11	69	mA	
					8 MHz	8.3	66	mA	
					4 MHz	5.9	63	mA	

1: T_A = +25 °C, V_{CC} = 3.3 V

2: T_J = +125 °C, V_{CC} = 5.5 V

3: When all ports are input and are fixed at 0

4: Frequency is a value of HCLK when PCLK0 = PCLK1 = PCLK2 = HCLK

5: When operating flash 0 wait-cycle mode and read access 0 wait (FRWTR.RWT = 00, FBFCR.SD = 000)

6: With data access to a MainFlash memory.

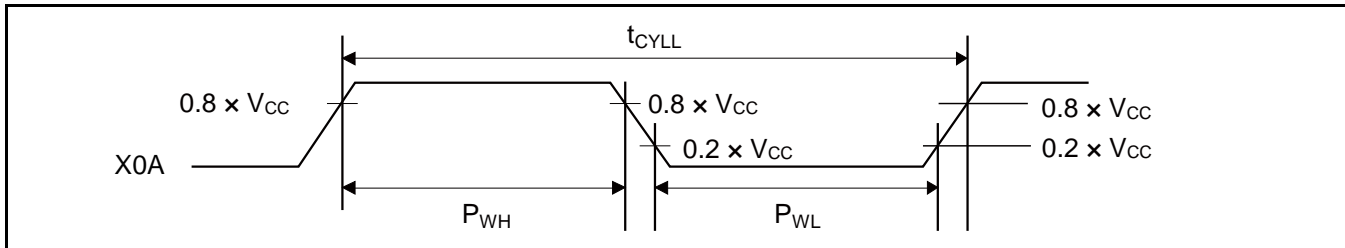
7: When using the crystal oscillator of 4 MHz (including the current consumption of the oscillation circuit)

12.4.2 Sub Clock Input Characteristics

($V_{CC} = 2.7V$ to $5.5V$, $V_{SS} = 0V$)

Parameter	Symbol	Pin Name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Input frequency	$1/t_{CYLL}$	X0A, X1A	-	-	32.768	-	kHz	When crystal oscillator is connected *
			-	32	-	100	kHz	When using external clock
Input clock cycle	t_{CYLL}		-	10	-	31.25	μs	When using external clock
Input clock pulse width	-		P_{WH}/t_{CYLL} , P_{WL}/t_{CYLL}	45	-	55	%	When using external clock

*: For more information about crystal oscillator, see Sub crystal oscillator in 9. Handling Devices.



12.4.3 Built-In CR Oscillation Characteristics

Built-In High-speed CR

($V_{CC} = 2.7V$ to $5.5V$, $V_{SS} = 0V$)

Parameter	Symbol	Conditions	Value			Unit	Remarks
			Min	Typ	Max		
Clock frequency	f_{CRH}	$T_J = -20^{\circ}C$ to $+105^{\circ}C$	3.92	4	4.08	MHz	When trimmed *1
		$T_J = -40^{\circ}C$ to $+125^{\circ}C$	3.88	4	4.12		
		$T_J = -40^{\circ}C$ to $+125^{\circ}C$	2.9	4	5		When not trimmed
Frequency stabilization time	t_{CRWT}	-	-	-	30	μs	*2

1: In the case of using the values in CR trimming area of flash memory at shipment for frequency/temperature trimming

2: This is the time to stabilize the frequency of the High-speed CR clock after setting trimming value. During this period, it is able to use the High-speed CR clock as a source clock.

Built-In Low-speed CR

($V_{CC} = 2.7V$ to $5.5V$, $V_{SS} = 0V$)

Parameter	Symbol	Condition	Value			Unit	Remarks
			Min	Typ	Max		
Clock frequency	f_{CRL}	-	50	100	150	kHz	

12.4.10 External Bus Timing

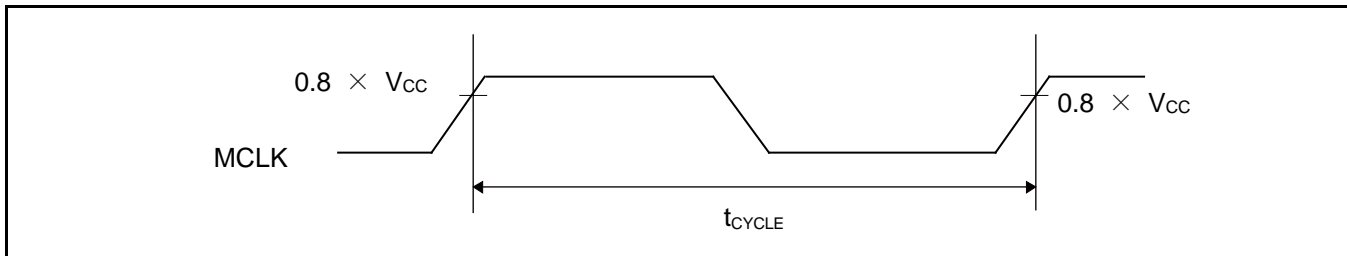
External Bus Clock Output Characteristics

Parameter	Symbol	Pin Name	Conditions	Value		Unit	Remarks
				Min	Max		
Output frequency	t_{CYCLE}	MCLKOUT *1		-	50 *2	MHz	

1: The external bus clock (MCLKOUT) is a divided clock of HCLK.

For more information about setting of clock divider, see Chapter 14: External Bus Interface in FM4 Family Peripheral Manual Main Part (002-04856).

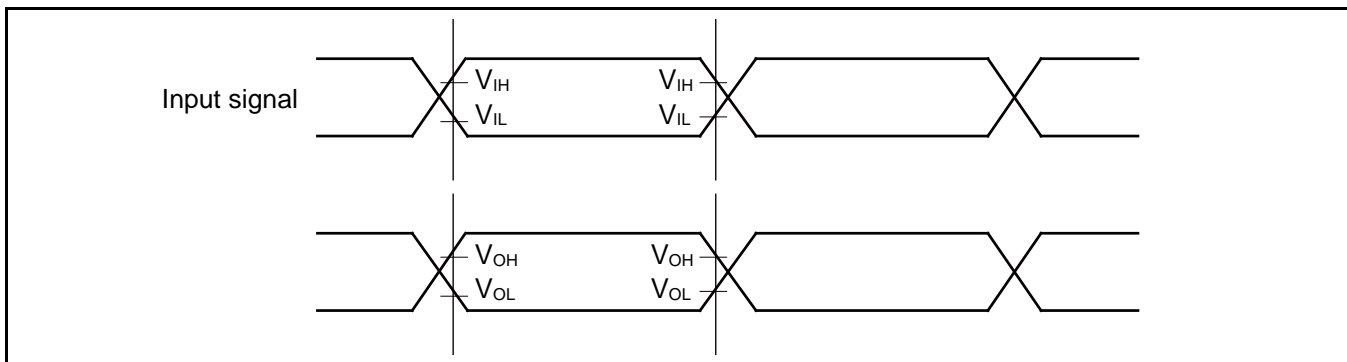
2: Generate MCLKOUT at setting more than four divisions when the AHB bus clock exceeds 100 MHz.

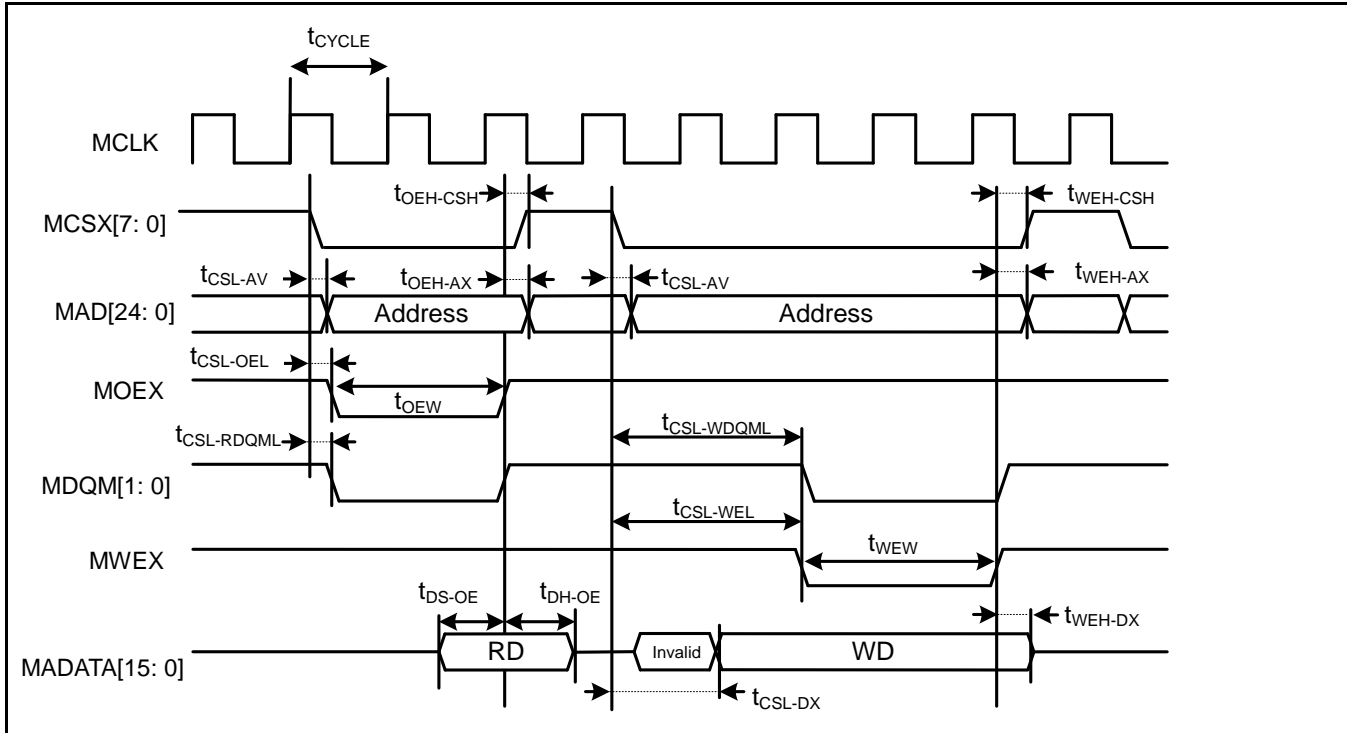


External Bus Signal I/O Characteristics

($V_{CC} = 2.7V$ to $5.5V$, $V_{SS} = 0V$)

Parameter	Symbol	Conditions	Value	Unit	Remarks
Signal input characteristics	V_{IH}	-	$0.8 \times V_{CC}$	V	
	V_{IL}		$0.2 \times V_{CC}$	V	
Signal output characteristics	V_{OH}		$0.8 \times V_{CC}$	V	
	V_{OL}		$0.2 \times V_{CC}$	V	





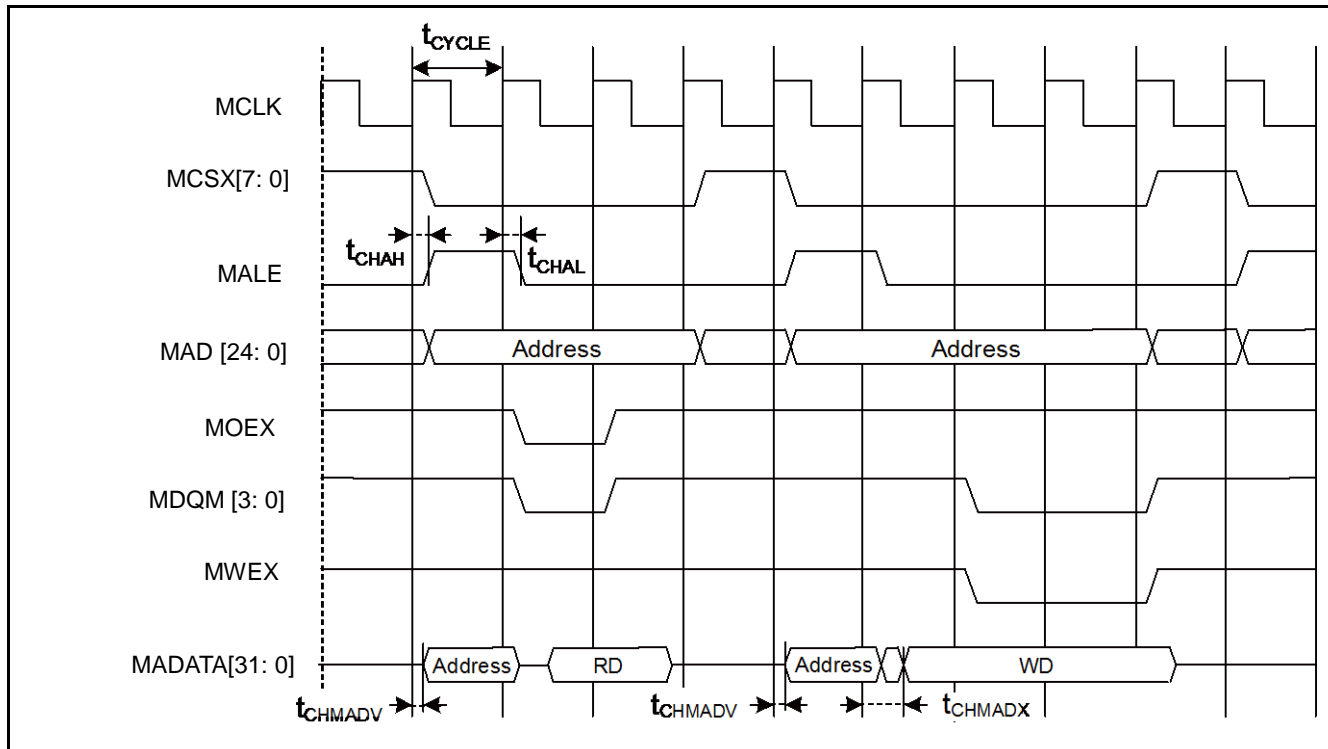
Multiplexed Bus Access Synchronous SRAM Mode

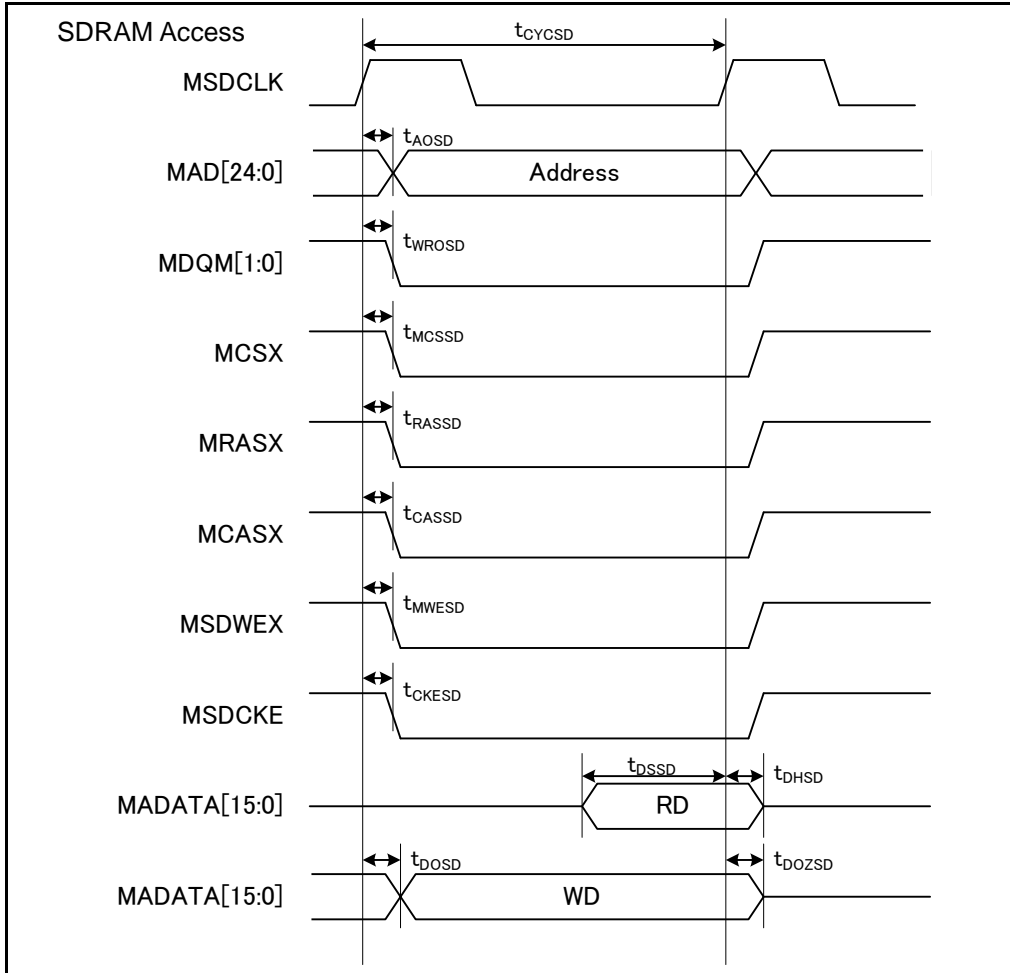
 (V_{CC} = 2.7V to 5.5V, V_{SS} = 0V)

Parameter	Symbol	Pin Name	Conditions	Value		Unit	Remarks
				Min	Max		
MALE delay time	t _{CHAL}	MCLK, MALE	-	1	9		
	t _{CHAH}		-	1	9		
MCLK ↑ → Multiplexed address delay time	t _{CHMADV}	MCLK, MADATA[31: 0]	-	1	t _{OD}	ns	
MCLK ↑ → Multiplexed data output time	t _{CHMADX}		-	1	t _{OD}	ns	

Note:

- When the external load capacitance C_L = 30 pF





12.4.12 CSIO (SPI) Timing

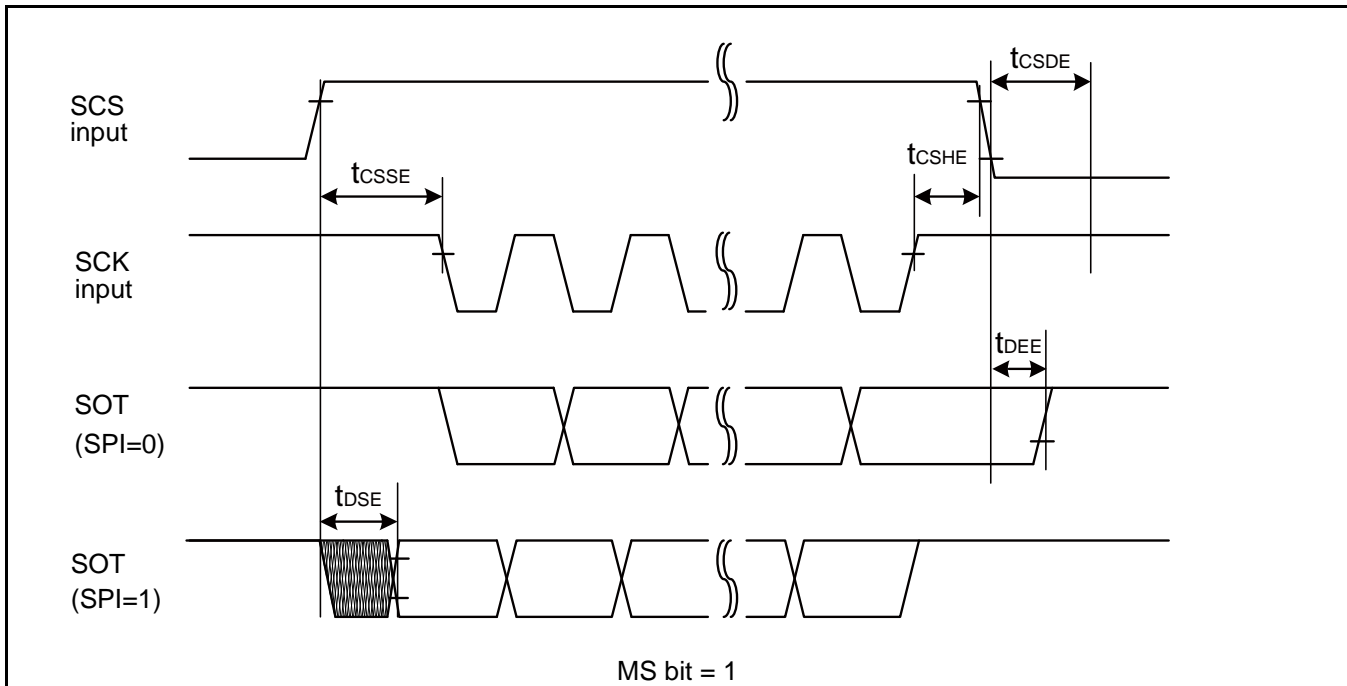
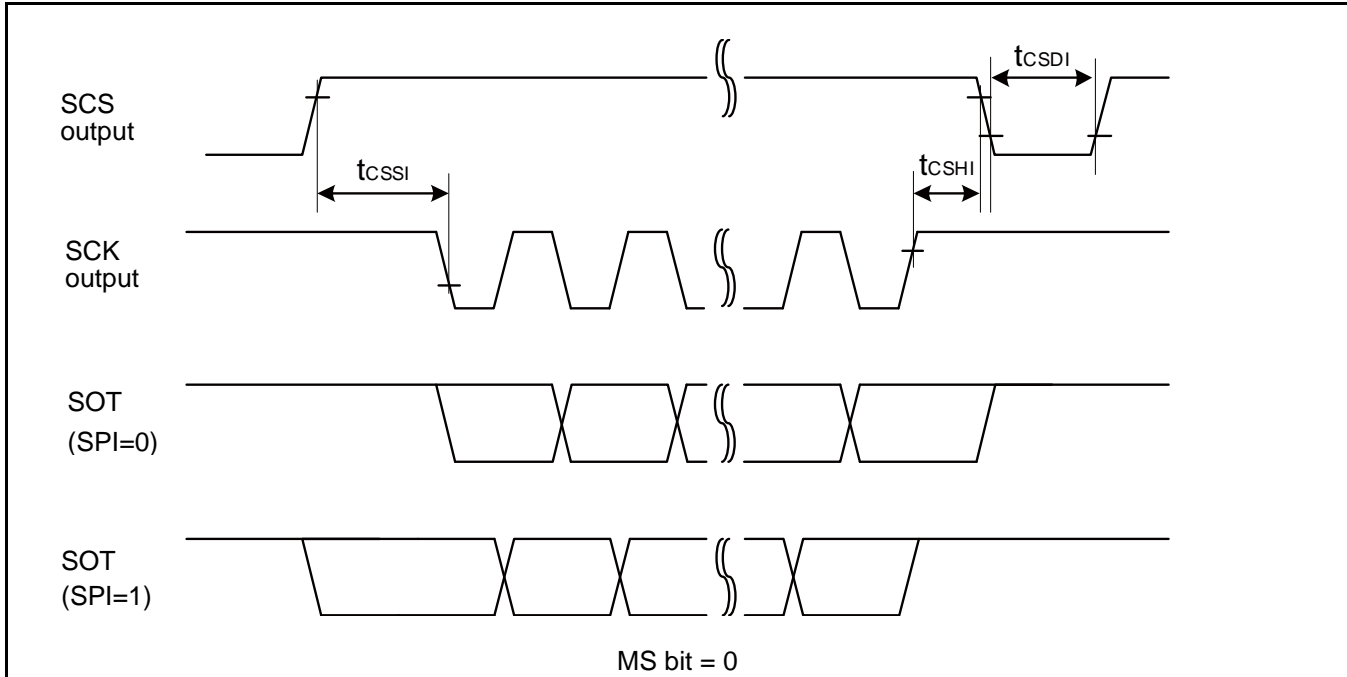
Synchronous Serial (SPI = 0, SCINV = 0)

(V_{CC} = 2.7V to 5.5V, V_{SS} = 0V)

Parameter	Symbol	Pin Name	Conditions	V _{CC} < 4.5 V		V _{CC} ≥ 4.5 V		Unit
				Min	Max	Min	Max	
Baud rate	-	-	-	-	8	-	8	Mbps
Serial clock cycle time	t _{SCYC}	SCKx	Internal shift clock operation	4t _{CYCP}	-	4t _{CYCP}	-	ns
SCK _↓ →SOT delay time	t _{SLOV}	SCKx, SOTx		- 30	+ 30	- 20	+ 20	ns
SIN→SCK _↑ setup time	t _{IVSHI}	SCKx, SINx		50	-	30	-	ns
SCK _↑ →SIN hold time	t _{SHIX}	SCKx, SINx		0	-	0	-	ns
Serial clock L pulse width	t _{SLSH}	SCKx	External shift clock operation	2t _{CYCP} - 10	-	2t _{CYCP} - 10	-	ns
Serial clock H pulse width	t _{SHSL}	SCKx		t _{CYCP} + 10	-	t _{CYCP} + 10	-	ns
SCK _↓ →SOT delay time	t _{SLOVE}	SCKx, SOTx		-	50	-	30	ns
SIN→SCK _↑ setup time	t _{IVSHE}	SCKx, SINx		10	-	10	-	ns
SCK _↑ →SIN hold time	t _{SHIXE}	SCKx, SINx		20	-	20	-	ns
SCK fall time	t _F	SCKx		-	5	-	5	ns
SCK rise time	t _R	SCKx		-	5	-	5	ns

Notes:

- The above characteristics apply to CLK synchronous mode.
- t_{CYCP} indicates the APB bus clock cycle time. For more information about the APB bus number to which the multi-function serial is connected, see 1. S6E2G Series Block Diagram in this data sheet.
- These characteristics only guarantee the same relocate port number; for example, the combination of SCLKx_0 and SOTx_1 is not guaranteed.
- When the external load capacitance C_L = 30 pF.



When Using High-Speed Synchronous Serial Chip Select (SCINV = 1, CSLVL = 0)
 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$

Parameter	Symbol	Conditions	$V_{CC} < 4.5 V$		$V_{CC} \geq 4.5 V$		Unit
			Min	Max	Min	Max	
SCS↓→SCK↓ setup time	t_{CSSI}	Internal shift clock operation	(*1)-20	(*1)+0	(*1)-20	(*1)+0	ns
SCK↑→SCS↓ hold time	t_{CSHI}		(*2)+0	(*2)+20	(*2)+0	(*2)+20	ns
SCS deselect time	t_{CSDI}		(*3)-20 +5 t_{CYCP}	(*3)+20 +5 t_{CYCP}	(*3)-20 +5 t_{CYCP}	(*3)+20 +5 t_{CYCP}	ns
SCS↑→SCK↑ setup time	t_{CSSE}	External shift clock operation	3 t_{CYCP} +15	-	3 t_{CYCP} +15	-	ns
SCK↓→SCS↓ hold time	t_{CSHE}		0	-	0	-	ns
SCS deselect time	t_{CSDE}		3 t_{CYCP} +15	-	3 t_{CYCP} +15	-	ns
SCS↑→SOT delay time	t_{DSE}		-	40	-	40	ns
SCS↓→SOT delay time	t_{DEE}		0	-	0	-	ns

(*1): CSSU bit value × serial chip select timing operating clock cycle [ns]

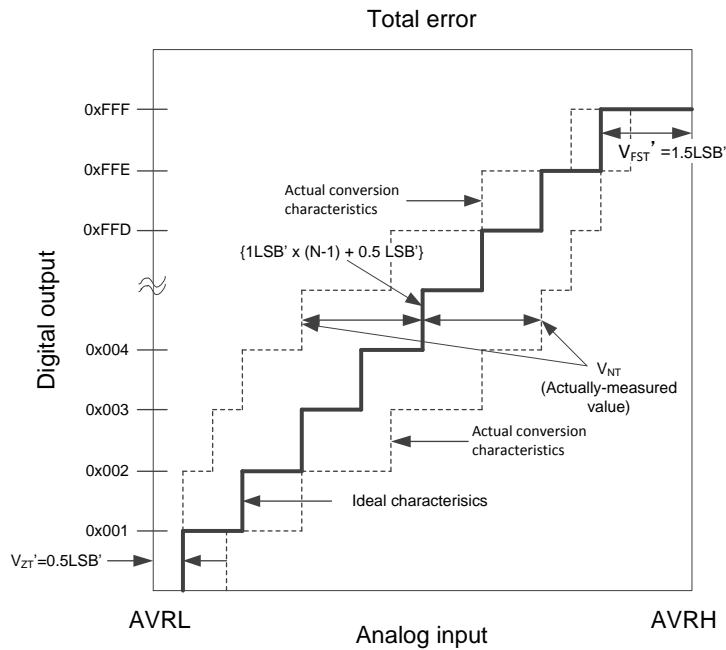
(*2): CSHD bit value × serial chip select timing operating clock cycle [ns]

(*3): CSDS bit value × serial chip select timing operating clock cycle [ns]

Notes:

- t_{CYCP} indicates the APB bus clock cycle time. For more information about the APB bus number to which the multi-function serial is connected, see 1. S6E2G Series Block Diagram in this data sheet.
- For more information about CSSU, CSHD, CSDS, and the serial chip select timing operating clock, see FM4 Family Peripheral Manual Main Part (002-04856).
- When the external load capacitance $C_L = 30 \text{ pF}$.

- **Total error:** A difference between actual value and theoretical value.
The overall error includes zero-transition voltage, full-scale transition voltage and linearity error.



$$\text{Total error of digital output } N = \frac{V_{NT} - \{1 \text{ LSB}' \times (N-1) + 0.5 \text{ LSB}'\}}{1 \text{ LSB}'} \quad [\text{LSB}]$$

$$1 \text{ LSB}' \text{ (ideal value)} = \frac{AVRH - AVRL}{4096} \quad [\text{V}]$$

$$V_{ZT}' \text{ (ideal value)} = AVRL + 0.5 \text{ LSB}' \quad [\text{V}]$$

$$V_{FST}' \text{ (ideal value)} = AVRH - 1.5 \text{ LSB}' \quad [\text{V}]$$

V_{NT}' : A voltage for causing transition of digital output from (N-1) to N

12.8 MainFlash Memory Write/Erase Characteristics

(V_{CC} = 2.7V to 5.5V)

Parameter		Value			Unit	Remarks
		Min	Typ	Max		
Sector erase time	Large Sector	-	0.7	3.7	s	Includes write time prior to internal erase
	Small Sector	-	0.3	1.1	s	
Half word (16-bit) write time	Write cycles ≤ 100 times	-	12	100	μs	Not including system-level overhead time
	Write cycles > 100 times			200		
Chip erase time*		-	13.6	68	s	Includes write time prior to internal erase

*: It indicates the chip erase time of 1MB MainFlash memory

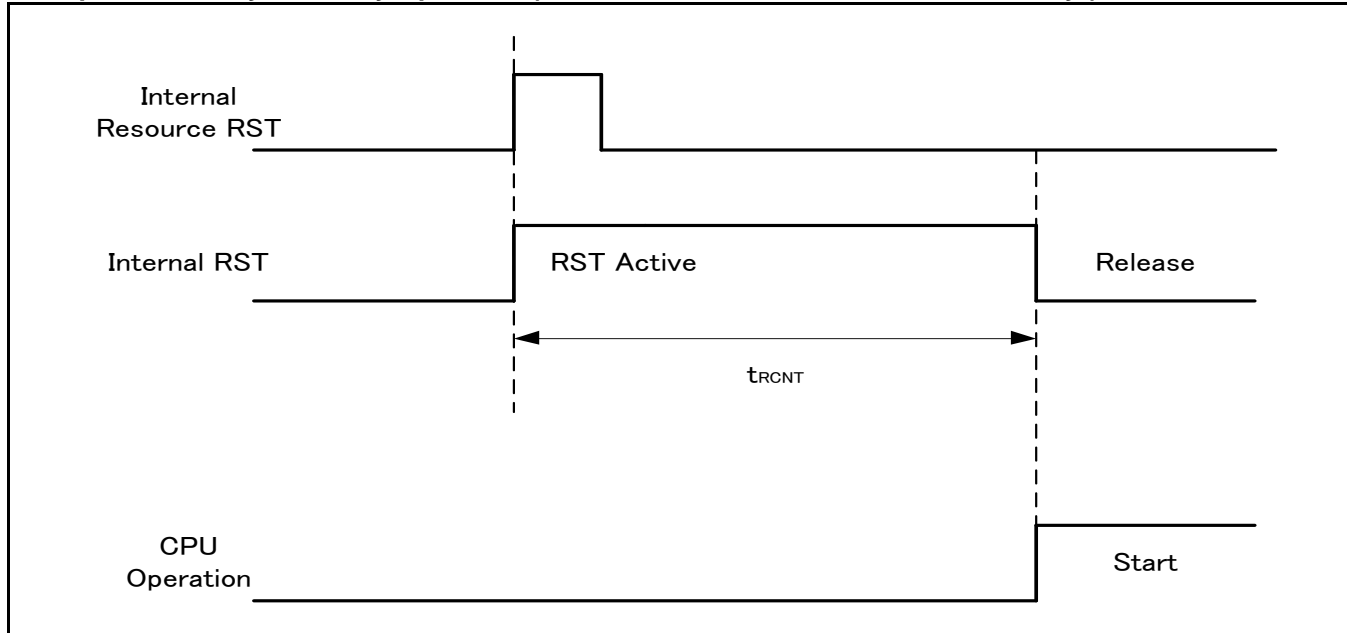
For devices with 1.5 MB or 2 MB of MainFlash memory, two erase cycles are required.

See 3.2.2 Command Operating Explanations and 3.3.3 Flash Erase Operation in this product's Flash Programming Manual for the detail.

Write Cycles and Data Retention Time

Erase/Write Cycles (Cycle)	Data Retention Time (Year)
1,000	20*
10,000	10*
100,000	5*

*: This value comes from the technology qualification (using Arrhenius equation to translate high temperature acceleration test result into average temperature value at + 85°C).

Example of Standby Recovery Operation (when in Internal Resource Reset Recovery*)


*: Depending on the low-power consumption mode, the reset issue from the internal resource is not included in the recovery cause.

Notes:

- The return factor is different in each low power consumption mode. See Chapter 6: Low Power Consumption mode and Operations of Standby modes in "FM4 Family Peripheral Manual Main Part (002-04856)".
- The recovery process is unique for each operating mode. See Chapter 6: Low Power Consumption mode in FM4 Family Peripheral Manual Main Part (002-04856).
- When the power-on reset/low-voltage detection reset, they are not included in the return factor. See 12.4.8 Power-On Reset Timing.
- In recovering from reset, CPU changes to High-speed Run mode. In the case of using the main clock and PLL clock, they need further main clock oscillation stabilization wait time and oscillation stabilization wait time of Main PLL clock.
- Internal resource reset indicates Watchdog reset and CSV reset.